

BILLING CODE 3510-DS-P

DEPARTMENT OF COMMERCE

International Trade Administration
Harvard University, et al.

Notice of Consolidated Decision on Applications for Duty-Free Entry of Electron Microscope

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials

Importation Act of 1966 (Pub. L. 89-651, as amended by Pub. L. 106-36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 A.M. and 5:00 P.M. in Room 3720, U.S. Department of Commerce, 14th and Constitution Avenue, NW, Washington, D.C.

Docket Number: 14-031. Applicant: Harvard University,
Cambridge, MA 02138. Instrument: Electron Microscope.
Manufacturer: JEOL Ltd., Japan. Intended Use: See notice
at 80 FR 2914-15, January 21, 2015.

Docket Number: 14-033. Applicant: University of South Carolina School of Medicine, Columbia, SC 29208.

Instrument: Electron Microscope. Manufacturer: JEOL Ltd.,

Japan. Intended Use: See notice at 80 FR 2914-15, January 21, 2015.

Docket Number: 14-036. Applicant: University of Michigan,
Ann Arbor, MI 48109-2200. Instrument: Electron
Microscope. Manufacturer: JEOL Ltd., Japan. Intended Use:
See notice at 80 FR 2914-15, January 21, 2015.

Docket Number: 14-037. Applicant: University of Arizona,
Tucson, AZ 85721. Instrument: Electron Microscope.

Manufacturer: FEI Company, Czech Republic. Intended Use:
See notice at 80 FR 2914-15, January 21, 2015.

Docket Number: 14-038. Applicant: University of North

Dakota, Grand Forks, ND 58202-8153. Instrument: Electron

Microscope. Manufacturer: FEI Company, Czech Republic.

Intended Use: See notice at 80 FR 2914-15, January 21,

2015.

Comments: None received. Decision: Approved. No instrument of equivalent scientific value to the foreign

instrument, for such purposes as this instrument is intended to be used, is being manufactured in the United States at the time the instrument was ordered. Reasons: Each foreign instrument is an electron microscope and is intended for research or scientific educational uses requiring an electron microscope. We know of no electron microscope, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of each instrument.

Gregory W. Campbell Director Subsidies Enforcement Office Enforcement and Compliance

April 24, 2015.

Date

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